

**Notice of References Cited**

Application/Control No.

10/584,729

Applicant(s)/Patent Under

Reexamination

TANAKA ET AL.

Examiner

Caridad M. Everhart

Art Unit

2891

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0070352	06-2002	ALLAN et al.	250/492.1
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**NON-PATENT DOCUMENTS**

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